

**FCC ID: 2ASV5-EAR102**

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$  for 1-g SAR and  $\leq 7.5$  for 10-g extremity SAR, where:

- f(GHz) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculatio n	SAR Exclusion threshold	SAR test exclusion
GFSK (BLE)	2.402	-6.273	0.24	-7±1	-6	0.25	<5	0.07786	3.00	YES
	2.44	-7.830	0.16	-7±1	-6	0.25	<5	0.07847	3.00	YES
	2.480	-7.541	0.18	-7±1	-6	0.25	<5	0.07911	3.00	YES
GFSK	2.402	-5.695	0.27	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.44	-5.742	0.27	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.511	0.28	-5±1	-4	0.40	<5	0.12539	3.00	YES
π/4-DQPSK	2.402	-7.737	0.17	-7±1	-6	0.25	<5	0.07786	3.00	YES
	2.44	-7.897	0.16	-7±1	-6	0.25	<5	0.07847	3.00	YES
	2.480	-7.214	0.19	-7±1	-6	0.25	<5	0.07911	3.00	YES
8-DPSK	2.402	-7.579	0.17	-7±1	-6	0.25	<5	0.07786	3.00	YES
	2.44	-7.641	0.17	-7±1	-6	0.25	<5	0.07847	3.00	YES
	2.480	-7.816	0.17	-7±1	-6	0.25	<5	0.07911	3.00	YES

**Conclusion:**

For the max result :  $0.12539\text{W/Kg} \leq 3.0$  for 1g SAR, No SAR is required.

**Signature:**

**Date:** 2020-04-16

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